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Applicant(s)/Patent under Reexamination

10/721,075

TANAKA, KOICHIRO
Art Unit

Examiner

1725

M. Alexandra Elve

SEARCHED			
Class	Subclass	Date	Examiner
update			
219	121.76	12/31/2006	MAE
219	121.78	12/31/2006	MAE
219	121.81	12/31/2006	MAE
219	121.85	12/31/2006	MAE
219	121.65	12/31/2006	MAE
219	121.66	12/31/2006	MAE

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
update US OCR, US PAT, US PG, Derwent, EPO, JPO, FPAS	12/30/2006	MAE
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